

SANYO

No. 4327

256 K (32768 words × 8 bits) SRAM

Overview

The LC36256ALL, AMLL-70/85/10/12 are fully asynchronous silicon gate CMOS static RAMs with an 32768 words × 8 bits.

This series has **CE** chip enable pin for device select/nonselect control and an **OE** output enable pin for output control, and features high speed as well as low power dissipation.

Current dissipation is notably reduced during stand-by and data retention. For these reasons, this series is most suited for use in systems requiring high speed, low power consumption and long-term battery backup. Simple memory capacity expansion is also supported.

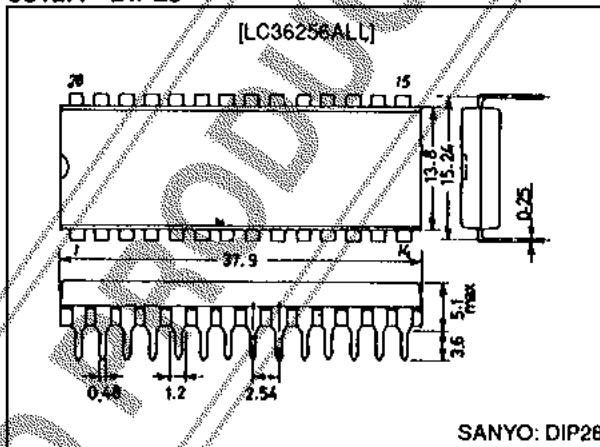
Features

- Access time
 - 70 ns (max.) : LC36256ALL-70, LC36256AMLL-70
 - 85 ns (max.) : LC36256ALL-85, LC36256AMLL-85
 - 100 ns (max.) : LC36256ALL-10, LC36256AMLL-10
 - 120 ns (max.) : LC36256ALL-12, LC36256AMLL-12
- Low current dissipation
 - During standby
 - 0.5 μ A (max.) / Ta = 25°C
 - 1 μ A (max.) / Ta = 0 to 40°C
 - 5 μ A (max.) / Ta = 0 to 70°C
 - During data retention
 - 0.3 μ A (max.) / Ta = 25°C
 - 0.6 μ A (max.) / Ta = 0 to 40°C
 - 3 μ A (max.) / Ta = 0 to 70°C
 - During operation (DC)
 - 10 mA (max.)
- Single 5 V power supply: 5 V ±10%
- Data retention power supply voltage: 2.0 to 5.5 V
- No clock required (Fully static memory)
- All input/output levels are TTL compatible
- Common input/output pins, with three output states
- Packages
 - DIP 28-pin plastic package (600 mil) : LC36256ALL
 - SOP 28-pin plastic package (450 mil) : LC36256AMLL

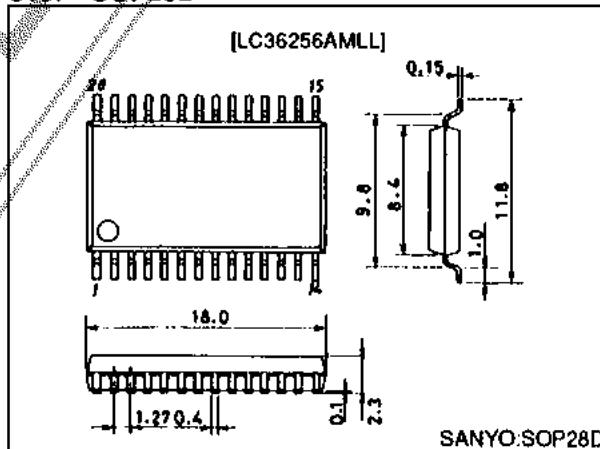
Package Dimensions

unit : mm

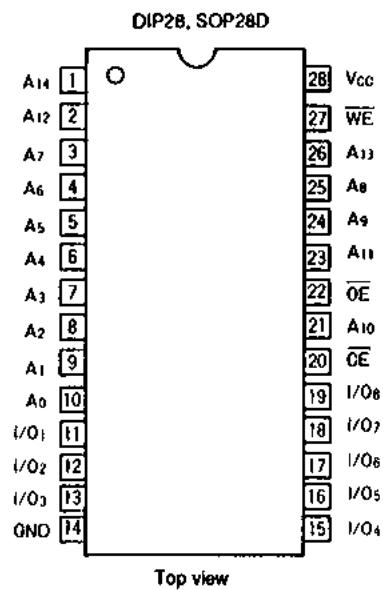
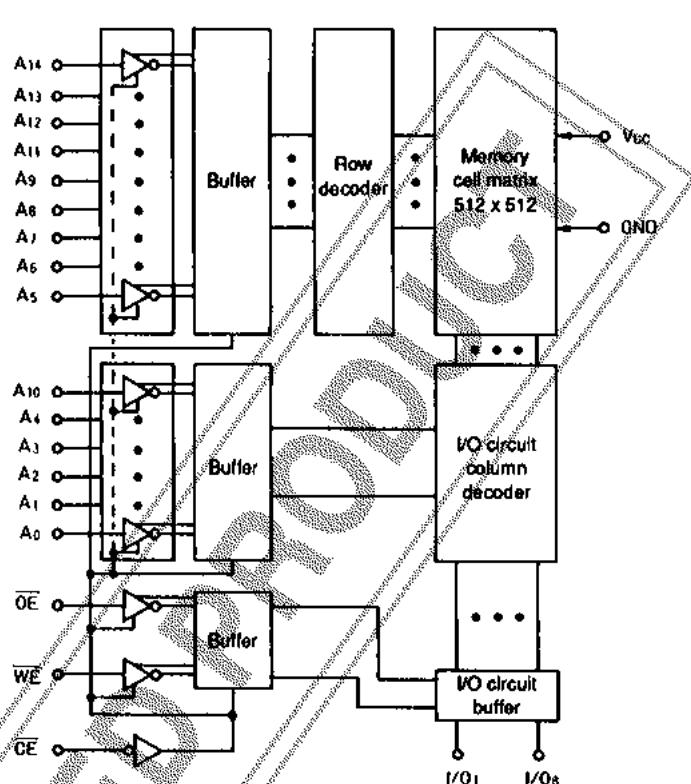
3012A - DIP28



3187 - SOP28D


SANYO Electric Co., Ltd. Semiconductor Business Headquarters

TOKYO OFFICE Tokyo Bldg., 1-10, 1 Chome, Ueno, Taito-ku, TOKYO JAPAN

Pin Assignment**Block Diagram**

- A1 to A14 : Address input
- WE : Read/write control input
- OE : Output enable input
- CE : Chip enable input
- I/O1 to I/O8 : Data input/output
- VCC, GND : Power supply pins

Functions

Mode	CE	OE	WE	I/O	Supply current
Read cycle	L	L	H	Data output	ICCA
Write cycle	L	X	L	Data input	ICCA
Output disable	L	H	H	High impedance	ICCA
Nonselect	H	X	X	High impedance	ICCS

X : H or L

Specifications

Absolute Maximum Ratings at $T_a = 25^\circ\text{C}$

Parameter	Symbol	Conditions	Ratings	Unit
Maximum supply voltage	V _{CC} max		7.0	V
Input pin voltage	V _{IN}		-0.5* to V _{CC} +0.5	V
I/O pin voltage	V _{IO}		-0.5* to V _{CC} +0.5	V
Allowable power dissipation	P _d max	LC36256ALL	1.0	W
		LC36256AMLL	0.7	W
Operating temperature range	T _{OPR}		0 to +70	°C
Storage temperature range	T _{STG}		-55 to +150	°C

* -3.0 V when pulse width is less than 50 ns

DC Recommended Operating Ranges at $T_a = 0$ to 70°C

Parameter	Symbol	min	typ	max	Unit
Power supply voltage	V _{CC}	4.5	5.0	5.5	V
Input high level voltage	V _{IH}	2.2		V _{CC} +0.3	V
Input low level voltage	V _{IL}	-0.3*		+0.8	V

* -3.0 V when pulse width is less than 50 ns

DC Electrical Characteristics at $T_a = 0$ to 70°C , $V_{CC} = 5 \text{ V} \pm 10\%$

Parameter	Symbol	Conditions			min	typ*	max	Unit
Input leakage current	I _{LI}	V _{IN} = 0 to V _{CC}			-0.5		+0.5	µA
I/O leakage current	I _{LO}	V _{CE} = V _{IL} or V _{OE} = V _{IH} , V _{IO} = 0 to V _{CC}			-0.5		+0.5	µA
Output high level voltage	V _{OH}	I _{OH} = -1.0mA			2.4			V
Output low level voltage	V _{OL}	I _{OL} = 2.1mA					0.4	V
Operating supply current (DC)	I _{CCA1}	V _{CE} ≤ 0.2V, V _{IN} ≤ 0.2V or V _{IN} ≥ V _{CC} -0.2V			1	5		mA
	I _{CCA2}	V _{CE} = V _{IL} , I _{IO} =0mA			3	10		mA
Average operating supply current	I _{CCA3}	min cycle Duty = 100% I _{IO} = 0mA	Access time	70ns	30	50		mA
				85ns	25	50		
				100ns	23	50		
				120ns	20	50		
Standby supply current	I _{CCS1}	V _{CE} ≥ V _{CC} -0.2V	LC36256ALL/ AMLL	0 to 70°C			5	µA
				0 to 40°C			1	
				25°C		0.2	0.5	
	I _{CCS2}	V _{CE} = V _{IH}			0.4	2		mA

* Reference values at $V_{CC} = 5 \text{ V}$, $T_a = 25^\circ\text{C}$

Input/Output Capacitance at Ta = 25°C, f = 1 MHz

Parameter	Symbol	Conditions	min	typ	max	Unit
Input/output capacitance	C _{IO}	V _{IO} = 0V			8	pF
Input capacitance	C _{IN}	V _{IN} = 0V			6	pF

Note: These parameters were obtained through sampling, and not full-lot measurement.

AC Electrical Characteristics at Ta = 0 to 70°C, V_{CC} = 5 V ±10%**AC testing conditions**

- Input pulse voltage level : 0.8 V, 2.2 V
 Input rise and fall time : 5 ns
 Input - output timing level : 1.5 V
 Output load : 1 TTL gate + C_L = 100 pF (85 ns/100 ns/120 ns)
 1 TTL gate + C_L = 30 pF (70 ns)
 (including scope and jig capacitance)

Read Cycle

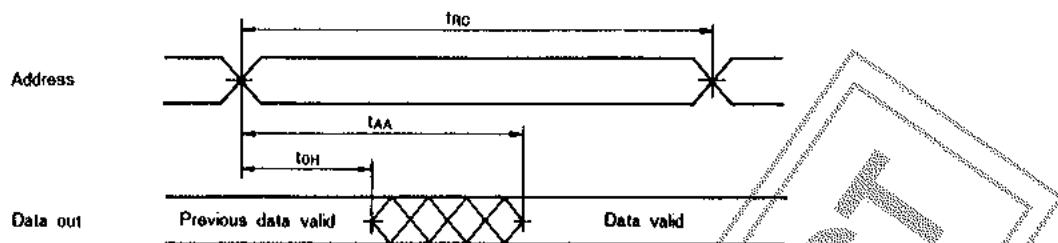
Parameter	Symbol	LC36256ALL-70		LC36256ALL-85		LC36256ALL-10		LC36256ALL-12		Unit
		min	max	min	max	min	max	min	max	
Read cycle time	t _{RC}	70		85		100		120		ns
Address access time	t _{AA}		70		85		100		120	ns
CE access time	t _{CA}		70		85		100		120	ns
OE access time	t _{OA}		35		45		50		60	ns
Output hold time	t _{OH}	20		20		20		20		ns
CE output enable time	t _{COE}	10		10		10		10		ns
OE output enable time	t _{COE}	5		5		5		5		ns
CE output disable time	t _{COD}	0	30	0	30	0	30	0	30	ns
OE output disable time	t _{OOD}	0	30	0	30	0	30	0	30	ns

Write Cycle

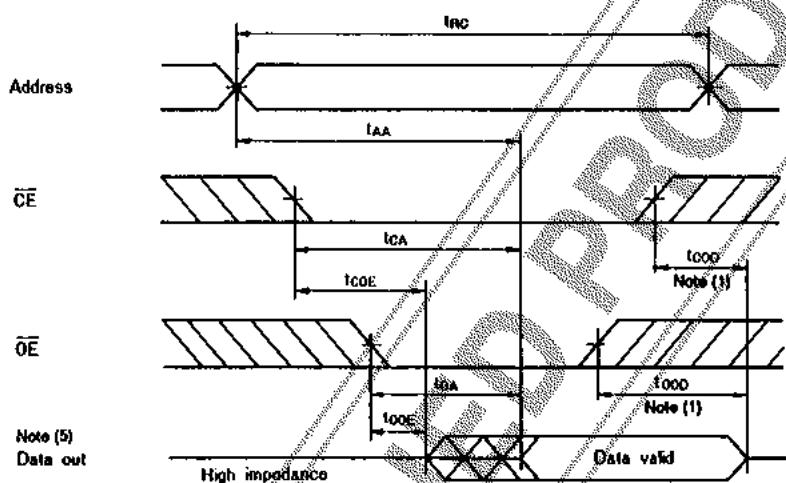
Parameter	Symbol	LC36256ALL-70		LC36256ALL-85		LC36256ALL-10		LC36256ALL-12		Unit
		min	max	min	max	min	max	min	max	
Write cycle time	t _{WC}	70		85		100		120		ns
Address valid to end of write	t _{AW}	65		75		80		100		ns
Address setup time	t _{AS}	0		0		0		0		ns
Write pulse width	t _{WP}	50		50		60		70		ns
CE setup time	t _{CW}	65		75		80		100		ns
Write recovery time (WE)	t _{WR}	0		0		0		0		ns
Write recovery time (CE)	t _{WR}	0		0		0		0		ns
Data setup time	t _{DS}	30		30		35		40		ns
Data hold time	t _{DH}	0		0		0		0		ns
WE output enable time	t _{WOE}	10		10		10		10		ns
WE output disable time	t _{WOD}	0	25	0	25	0	25	0	25	ns

Timing Chart

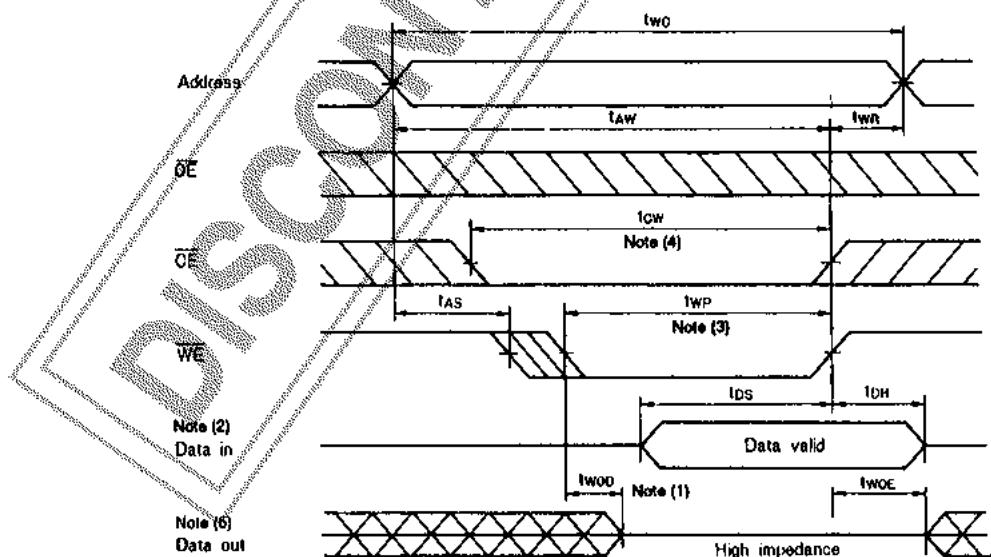
- Read Cycle (1): $\overline{CE} = \overline{OE} = V_{IL}$, $\overline{WE} = V_{IH}$



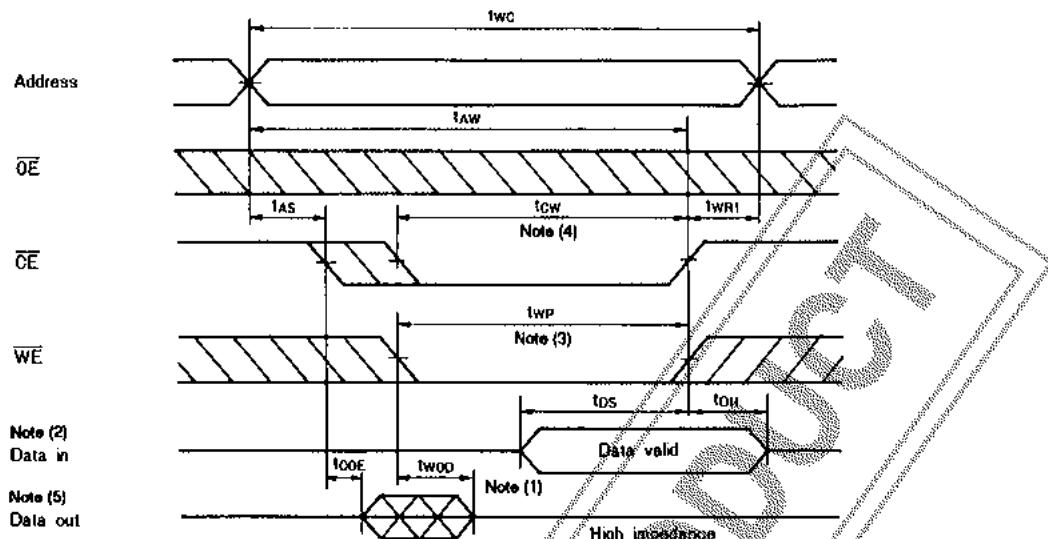
- Read Cycle (2): $\overline{WE} = V_{IH}$



- Write Cycle (1): \overline{WE} Control Note (6)



- Write Cycle (2): \overline{CE} Control Note (6)



- Notes
- (1) t_{OD} , t_{ODD} , and t_{ODD} are defined as the time at which the outputs becomes the high impedance state and are not referred to output voltage levels.
 - (2) An external antiphase signal must not be applied when DOUT is in the output state.
 - (3) t_{WP} is the time interval that \overline{CE} and \overline{WE} are low-level and is defined as the interval from the falling of \overline{WE} to the rising of \overline{CE} or \overline{WE} whichever is earlier.
 - (4) t_{CW} is the time interval that \overline{CE} and \overline{WE} are low-level and is defined as the time from the falling of \overline{CE} to the rising of \overline{CE} or \overline{WE} whichever is earlier.
 - (5) DOUT goes to the high-impedance state when either \overline{OE} is high-level, \overline{CE} is high-level, or \overline{WE} is low-level.
 - (6) When \overline{OE} is high-level during the write cycle, DOUT goes to the high-impedance state.

Data Retention Characteristics at $T_a = 0$ to 70°C

Parameter	Symbol	Conditions	LC36256ALL/AMLL			Unit
			min	typ*	max	
Data retention supply voltage	V_{DR}	$V_{CE} \geq V_{CC} - 0.2\text{V}$	2.0		5.5	V
Data retention supply current	I_{CCDR1}	$V_{CC} = 3.0\text{V}$			3	μA
		$V_{CE} \geq 2.8\text{V}$	0 to 70°C			
	I_{CCDR2}	$V_{CC} = 2.0$ to 5.5V , $V_{CE} \geq V_{CC} - 0.2\text{V}$	0 to 40°C		0.6	
\overline{CE} setup time	t_{CDR}			0.1	0.3	
\overline{CE} hold time	t_R			0.2	5	μA
					t_{RC}^{**}	ns

* Reference values at $V_{CC} = 5\text{V}$, $T_a = 25^\circ\text{C}$ ** t_{RC} = Read Cycle time

Data Retention Waveform

